

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Hisashi Ohtani et al. Art Unit : 2815
Serial No. : 09/379,702 Examiner : Eugene Lee
Filed : August 24, 1999 Conf. No. : 1613
Title : METHOD OF FABRICATING SEMICONDUCTOR DEVICES

MAIL STOP AF

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

INFORMATION DISCLOSURE STATEMENT

Applicants request consideration of the references listed on the attached PTO-1449 form.

This statement is being filed after a final Office action or a Notice of Allowance, but before payment of the issue fee. Each item of information in this statement (i) was cited in a communication from a foreign patent office in a counterpart foreign application, the communication being dated December 19, 2006, which is not more than three months prior to the filing of this statement, and (ii) was not first cited in any communication from a foreign patent office in a counterpart application which was more than three months prior to the filing date of this statement. A check for \$180 in payment of the late submission fee of §1.17(p) is enclosed. Please apply any other charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 1/16/07

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Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 07977-093002	Application No. 09/379,702
	Applicant Hisashi Ohtani et al.		
	Filing Date August 24, 1999	Group Art Unit 2815	

U.S. Patent Documents							
Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA						
	AB						
	AC						
	AD						
	AE						
	AF						
	AG						
	AH						
	AI						
	AJ						
	AK						

Foreign Patent Documents or Published Foreign Patent Applications								
Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
	AL	JP03-289140	12/19/1991	JAPAN			Abstract	
	AM	JP04-240733	08/28/1992	JAPAN			Abstract	
	AN							
	AO							
	AP							

Other Documents (include Author, Title, Date, and Place of Publication)		
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	AQ	
	AR	
	AS	
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Examiner Signature	Date Considered
EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.	